



## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

12 3 3

In re the Application of: Kenji WATANABE et al.

Art Unit: 2881

Application Number: 10/543,151

Examiner: Kiet T. Nguyen

Filed: April 18, 2006

Confirmation Number: 2634

For:

MAPPING-PROJECTION-TYPE ELECTRON BEAM APPARATUS FOR

INSPECTING SAMPLE BY USING ELECTRONS EMITTED FROM THE

**SAMPLE** 

Attorney Docket Number:

052886

Customer Number:

38834

## AMENDMENT UNDER 37 C.F.R. § 1.111

Mail Stop Amendment Commissioner for Patents P. O. Box 1450 Alexandria, VA 22313-1450 November 25, 2008

Sir:

This paper is filed in response to the Office Action dated August 25, 2008.

Amendments to the Claims begin on page 2 of this paper.

Remarks begin on page 7 of this paper.

Form PCT/DO/EO/903 is attached following page 10 of this paper.